



2024 INTERNATIONAL CONFERENCE ON RADIO FREQUENCY MEASUREMENT

CRFM

Conference Pamphlet

📅 September, 10-12, 2024

📍 Yining, CHINA





CONTENTS

会议须知	1
1. Introduction	2
2. Conference Committee	3
3. Program	5
4. Traffic Guidance	9
5. Contacts	10





会议须知

各位来宾、领导和专家：

您好！欢迎来到伊宁，参加2024年射频电子测量国际学术会议。会议有关事宜告知如下：

一、**会议日期**:2024年9月10日报到，9月11日-9月12日开会。

二、**会议地点**:伊宁伊犁宾馆。

9月11日：3号楼一楼多功能厅；9月12日：3号楼二楼那拉提厅。

三、会议期间凭会议餐券就餐，会议期间禁止饮酒。

四、遵守大会日程安排进入会场，请主动将手机设置在振动状态。需要接听到会场外以免影响大会进行。

五、集体活动请听从大会工作人员的安排，开会与活动期间请佩带代表证。





1. Introduction

2024 INTERNATIONAL CONFERENCE ON RADIO FREQUENCY MEASUREMENT (CRFM 2024) will be held in Yi Ning, Xinjiang, China in September 2024. Technical papers describing original work in research, development, and application of all areas in microwave and millimeter wave are solicited.

CRFM 2024 is organized by Professional Committee of Electronic Metrology, Chinese Society for Measurement (CSM)

CRFM2024 will feature parallel session tracks, workshops, and student and special sessions providing a platform for not only exchanges of innovative ideas but also opportunities for collaboration among people from academia and industry around the world.

Host: Professional Committee of Electronic Metrology

Organizers: Chinese Society for Measurement

Division of Electrical Information Metrology, National Institute of Metrology, China

Dates: September 10-12th, 2024

Venue: Yili Hotel

Address: No. 8 Yingbin Road, Yining, China





2. Conference Committee

Chair: Prof. Cui Xiaohai, National Institute of Metrology (NIM), China

Vice Director of the Committee

Prof. Miao Jungang, Beihang University, China

Prof. Ma Hongmei, Beijing Institute of Radio Metrology and Measurement, China

Prof. Si Liming, Beijing Institute of Technology, China

Prof. Wang Yong, The Fifth Electronics Research Institute of the Ministry of Industry and Information Technology, China

Prof. Wei Ping, Chengdu Aircraft Industry (Group) Co., Ltd, China

General Secretary

Prof. Liu Yitong, National Institute of Metrology, China

Paper Review Expert

Prof. Nick Ridler, NPL, UK.

Prof. Tian Hong Loh, NPL, UK

Prof. Lu Xifeng, NIST, USA

Prof. Natalian Der, Teradyne, USA

Prof. Gu Dazhen, NIST, USA

Prof. Wang Guoan, University of South Carolina, USA

Prof. Meng Yusong, NMC, Singapore

Ph.D Arshad Selamat, Universiti Kebangsaan Malaysia, Selangor, Malaysia

Prof. Li Xiuping, Beijing University of Posts and Telecommunications, China

Prof. Chen Wenhua, Tsinghua University, China

Prof. Zhao Ziran, Tsinghua University, China

Prof. Qiao Liyan, Harbin Institute of Technology, China

Prof. Zhu Jiangmiao, Beijing University of Technology, China

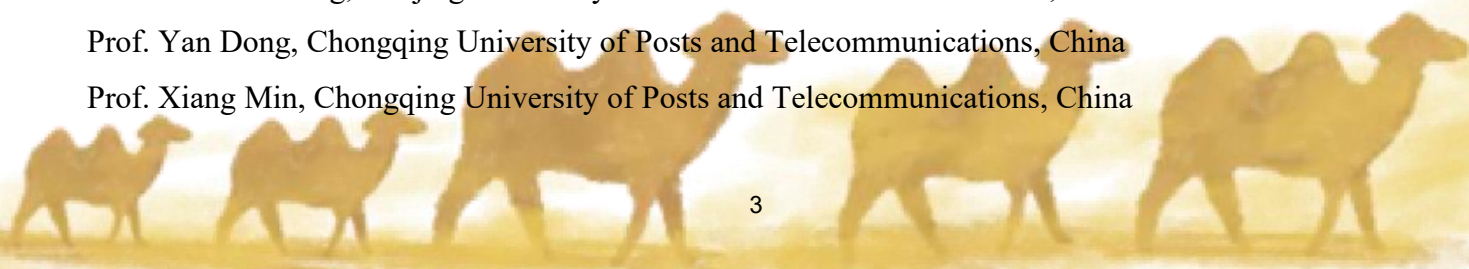
Prof. Yu Weihua, Beijing Institute of Technology, China

Prof. Gao Jinchun, Beijing University of Posts and Telecommunications, China

Prof. Du Guanxiang, Nanjing University of Posts and Telecommunications, China

Prof. Yan Dong, Chongqing University of Posts and Telecommunications, China

Prof. Xiang Min, Chongqing University of Posts and Telecommunications, China





Prof. Huang Qingqing, Chongqing University of Posts and Telecommunications, China

Prof. Hu Kunzhi, Chongqing University of Posts and Telecommunications, China

Prof. Li Xiangjun, China Jiliang University, China

Prof. Zhou Haomiao, China Jiliang University, China

Prof. Yang Chuang, Beijing University of Posts and Telecommunications, China

Prof. Zhou Shaohua, Zhongyuan University of Technology, China

Prof. Yan Yiming, Harbin Engineering University, China

Prof. Gao Ju, Beijing University of Technology, China

Prof. Ding Shuai, University of Electronic Science and Technology of China, China

Prof. Ren Jie, Beijing Jiaotong University, China

Prof. Qi Zihang, Beijing University of Posts and Telecommunications, China

Prof. Ding Hui, Capital Normal University, China

Prof. Yang Chuntao Beijing Institute of Radio Metrology and Measurement

Prof. Su Jiangtao, Hangzhou Dianzi University, China

Prof. Li Zhiping, Beihang University, China

Prof. Lu Hongmei, Xidian University, China

Prof. Zhang Yichi, National Institute of Metrology, China

Prof. Zhao Kejia, National Institute of Metrology, China

Prof. Huang Pan, National Institute of Metrology, China

Prof. Liu Xiao, National Institute of Metrology, China

Prof. Lin Haoyu, National Institute of Metrology, China

Prof. Li Difei, National Institute of Metrology, China

Prof. He Zhao, National Institute of Metrology, China

Prof. Meng Donglin, National Institute of Metrology, China

Publication Editor

Xu Hao, National Institute of Metrology, China





3. Program

CRFM OVERVIEW		
September 11th: Multi-functional Hall on the first floor of Building 3; September 12th: Nalati Hall, 2nd Floor, Building 3 9月11日: 3号楼一楼多功能厅; 9月12日: 3号楼二楼那拉提厅		
TIME		AFFAIR
September 10th	10:00-18:00	Registration
September 11th	10:00-10:10	Opening Ceremony
	10:10-11:10	Session 1: Keynote Speeches
	11:10-11:40	Tea Break & Group Photo
	11:40-13:40	Session 1: Keynote Speeches
	13:40-15:00	Lunch
	15:00-17:30	Session 1: Invited Talk
	17:30-18:00	Tea Break & Poster Session
	18:00-20:00	Session 1: Invited Talk
	20:00	Dinner
September 12th	10:00-11:00	Session 2: Invited Talk
	11:00-11:40	Tea Break & Poster Session
	11:40-13:20	Session 2: Oral Presentations
	13:20-15:00	Lunch
	15:00-18:00	Discussion
	18:00	Closing



Session 1: Measurement Challenges for Emerging RF-to-THz Technologies

Chair: Cui Xiaohai September 11th (10:00-15:00)

TIME	TYPE	TOPICS	NAME	AFFILIATION
10:00-10:10	Opening Ceremony			
10:10-10:40	Keynote Speech	The Nature of Metrology and Its Future Development	Prof. Ma Aiwen	CSM
10:40-11:10	Keynote Speech	Advancements in RF Parameters Metrology and Their Applications in the Field of Electronics	Prof. Cui Xiaohai	NIM
11:10-11:40	Tea Break & Group Photo			
11:40-12:10	Keynote Speech	Overview of a European Union Joint Research Project on Metrology for Emerging Wireless Standards	Prof. Tian Hong Loh	NPL, UK
12:10-12:40	Keynote Speech	Integration of Artificial Intelligence and Artificial Metamaterials: Theory and Applications	Prof. Si Liming	Beijing Institute of Technology
12:40-13:10	Keynote Speech	Some Recent Advances in Millimetre-wave and Terahertz Electrical Metrology at the UK's National Physical Laboratory	Prof. Nick Riddler	NPL, UK
13:10-13:40	Keynote Speech	International Metrology Organization and the Development of the World RF Metrology	Prof. Meng Yusong	NMC, Singapore
13:40-15:00	Lunch			



Session 1: Measurement Challenges for Emerging RF-to-THz Technologies

Chair: Liu Yitong September 11th (15:00-20:00)

TIME	TYPE	TOPICS	NAME	AFFILIATION
15:00-15:30	Invited Talk	The Development and Opportunities of Unmanned Aerial Vehicle System Testing and Certification	Prof. Li Feng	Xinjiang Uygur Autonomous Region Research Institute of Measurement Testing
15:30-16:00	Invited Talk	Characteristics Analysis of Target Simulator for Automotive Millimeter Wave Radar	Prof. Wang Weilong	NIM
16:00-16:30	Invited Talk	No Phase Precise AR Test for Circular Polarization Antenna	Prof. Zhang Xiaoping	Beijing Spacecraft General Design Department
16:30-17:00	Invited Talk	Physical Layer Characteristic Testing of High-speed Digital Link Based on Vector Network Parameters	Prof. Liang Shengli	CETC Ceyear Technologies Co., Ltd
17:00-17:30	Invited Talk	Research and Development of New RF Power Device Test Technology	Prof. Liu Xinai	Aerospace Information Research Institute Chinese Academy of Sciences
17:30-18:00	Tea Break & Poster Session			
18:00-18:30	Invited Talk	Research and Application of Coaxial Power Tracing Technology	Dr. Yuan Wenzhe	NIM
18:30-19:00	Invited Talk	Electromagnetic Characteristics of Multi-level Power Grid and Strong Electromagnetic Pulse Port Protection Technology for Special Vehicles	Wang Biao	China North Vehicle Research Institute
19:00-19:30	Invited Talk	Ultra Wideband THz Signal Generation and Analysis	Dr. Wang Jian	Rohde & Schwarz (China) Technology Co.,Ltd
19:30-20:00	Invited Talk	Millimeter Wave and Photoelectric Chip Measurement Challenges and Equipment Development	Nan Jianjun	Shanghai Matrix System Co., Ltd
20:00	Closing			



Session 2: Youth Forum

Chair: Li Difei September 12th (10:00-18:00)

TIME	TYPE	TOPICS	NAME	AFFILIATION
10:00-10:20	Invited Talk	Discussion on Metrological and Measurement Technology in Semiconductor Industry	Prof. Wu Aihua	CETC
10:20-10:40	Invited Talk	Research on the Metasurface of Atomic Gas Chamber for Miniaturized Atomic Clocks	Prof. He Tao	Tongji University
10:40-11:00	Invited Talk	Research on Application of TD-SVSWR Measurement Method for Anechoic Chamber Site Verification	Li Difei	NIM
11:00-11:40	Tea Break & Poster Session			
11:40-12:00	Oral Presentation	Artificial Intelligence Cleaning Robots and Their Reliability Practices	Lai Zhilin	Saite Intelligence Technology Co., Ltd
12:00-12:20	Oral Presentation	Intelligent Robot Industry Measurement Status and Challenges	Prof. Wang Zhirong	National Intelligent Industrial Robot Industry Measurement and Testing Center
12:20-12:40	Oral Presentation	Improvement Measurement of Photodetectors Response Characteristics Based on Electro-optic Sampling	Chen He	NIM
12:40-13:00	Oral presentation	Calibration Method Comparing and Calibration Factor Estimation of RF Directional Power Sensor	Xu Zekun	China Jiliang University
13:00-13:20	Oral presentation	Analysis and correction of atmospheric absorption attenuation in V-band antenna measurement	Li Ke	NIM
13:20-15:00	Lunch			
15:00-18:00	Discussion			
18:00	Closing			



4. Traffic Guidance

Conference Venue: Yi Li Hotel

Address: No. 8 Yingbin Road, Yining, China

Traffic (交通)	Route (路线)	
Yili Yining International Airport (6.5 kilometers)	Taxi	About 15 yuan. The entire journey takes about 16 minutes.
	Bus	Take Yining 19 Kaixuan City Line at Yining Airport Bus Station, get off at Kunlun Road Intersection Bus Station, transfer to Yining 301 Bus at the same station, get off at Youhao Tianbai Bus Station, and then walk for 7 minutes to Yili Hotel.
伊犁伊宁国际机场 (6.5 公里)	打车	约 16 分钟，15 元。
	公交	在伊宁机场公交站乘坐伊宁 19 路凯旋城线，到昆仑路路口公交站下车，同站换乘伊宁 301 路公交，到友好天百公交站下车，然后步行 7 分钟到达伊犁宾馆。



5. Contacts

Wangnan : 010-64525260 wangnan@nim.ac.cn

Xuhui : 010-64525202 xuhui@nim.ac.cn

Zhouqing : 15527883092 meetconf_zq@163.com



**ROHDE & SCHWARZ**

Make ideas real

**Rohde & Schwarz**

Rohde & Schwarz is striving for a safer and connected world with its Test & Measurement, Technology Systems and Networks & Cybersecurity Divisions. For 90 years, the global technology group has pushed technical boundaries with developments in cutting-edge technologies. The company's leading-edge products and solutions empower industrial, regulatory and government customers to attain technological and digital sovereignty. The privately owned, Munich based company can act independently, long-term and sustainably. Rohde & Schwarz generated net revenue of EUR 2.78 billion in the 2022/2023 fiscal year (July to June). On June 30, 2023, Rohde & Schwarz had around 13,800 employees worldwide.











